

Search Notes

Application/Control No.

10/069,596

Examiner

Hien Tran

Applicant(s)/Patent under
Reexamination

NAKAJIMA ET AL.

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner
422	177, 180, 171	5/19/2005	HT
updated	search	11/4/2005	HT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image class/subclass search / Inventors' names search / Text search	5/19/2005	HT